

TUZ 2024

Ph.D.
Forum



Darmstadt, February 25th to 27th 2024

36. ITG / GMM / GI - Workshop on Test Methods and Reliability of Circuits and Systems

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The Workshop on Test Methods and Reliability of Circuits and Systems is the most significant German forum to discuss trends, results and current problems in the area of test, diagnosis and reliability of digital, analog, mixed-signal and high-frequency-circuits. The exchange of ideas is an important intention of this workshop.

The TUZ Doctoral Forum is a newly introduced format that aims to promote the exchange of ideas, experiences and perspectives of young doctoral students in the field of test and reliability. The PhD students present their current research work in a poster session and are given the opportunity to discuss and receive feedback from specialists from both academia and industry. This new format also offers experts from industry and academia the opportunity to meet with young scientists.

We welcome research topics from the following areas, among others:

- Adaptive systems (e.g. self-repair, self-healing, self-awareness)
- Automatic test equipment, test automation, test programs and test modelling
- Defect and failure modeling
- Diagnosis of failure causes
- Fault tolerance, resilience, robust and radiation-resistant systems
- Functional safety
- Hardware-oriented test and hardware-oriented safety
- Statistical and machine learning techniques for test and reliability
- System test and reliability
- Test and simulation of mixed-signal, RF and analog circuits
- Test generation, fault simulation, self-test and online-test
- Design-For-Test, DFT methodology
- Test costs and test quality
- Test standards such as IEEE 1149.x, IEEE 1687.x, IEEE P1838

The workshop takes place at the Georg-Christoph-Lichtenberg-Haus in Darmstadt, Germany, and is organized by Technical University of Darmstadt.

Interested doctoral students are asked to submit a summary of their research activities and the results to date in a maximum of 2 pages via the workshop homepage. The contribution should describe the purpose of the research, the novelty content and aspects of a possible later application.



Workshop-Homepage

www.tuz-workshop.de

Submission-Site

<https://easychair.org/conferences/?conf=tuz24>

Important Dates

Deadline for paper submission: 28. Jan. 2024

Notification of acceptance: 31. Jan. 2024

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Organizer

GI FA 3.5 / GMM FA 6.5/ ITG FA 8.2 RSS Kooperationsgemeinschaft rechnergestützter Schaltungs- und Systementwurf



GMM

VDE ITG